

Resource Summary Report

Generated by [RRID](#) on Aug 6, 2026

FEI: Meridian 7 System for Semiconductors

RRID:SCR_019888

Type: Tool

Proper Citation

FEI: Meridian 7 System for Semiconductors (RRID:SCR_019888)

Resource Information

URL: <https://www.fei.com/products/efa/Meridian-7-for-Semiconductors/>

Proper Citation: FEI: Meridian 7 System for Semiconductors (RRID:SCR_019888)

Description: Electrical failure analysis system for semiconductors that provides visible laser voltage imaging and probing and dynamic laser stimulation on sub-10nm devices.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEdit,

Availability: Commercially available

Resource Name: FEI: Meridian 7 System for Semiconductors

Resource ID: SCR_019888

Alternate IDs: Model_Number_Meridian_7

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190647+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Meridian 7 System for Semiconductors.

No alerts have been found for FEI: Meridian 7 System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.